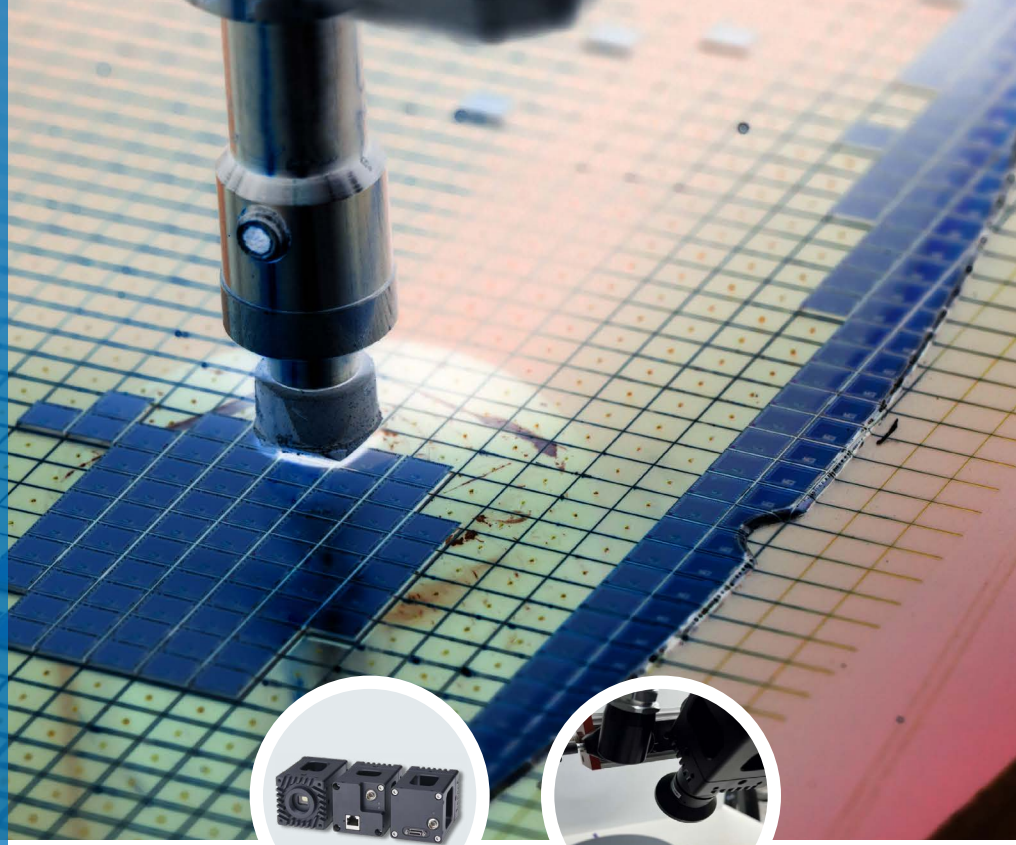


OMRON

solution GUIDE

Semiconductor Industry

IPA is dispensed on wafer. Coverage may be incomplete or extra drops may be left in excess. These need to be discovered so corrective action can be taken.



Key Features

- Sony Pregius IMX990 & IMX991 SWIR Sensors
- GigE Vision, USB3 Vision, and Camera Link Interfaces
- 0.3MP or 1.3MP resolution
- Fan-less Peltier Cooling Design allows industry leading cooling efficiency
- Compatible with a variety of Machine Vision software, short wave infrared lenses, lighting and more
- Removes environmental dependency and variability
- Product inspection capabilities through full production process

Segment

Wafer Manufacturing & Inspection

Customer Issue

Loss of Revenue due to Manufacturing of Faulty Wafers

Challenge

- The wafer itself is a mirror like surface which makes inspection difficult
- The Isopropyl Alcohol is clear and has extremely low surface tension so detecting the liquid is near impossible
- Traditional inspection methods cannot detect the IPA on the wafer due to the difficult qualities of the two substances



Part Number	Interface	Resolution	Frame Rate	Sensor Size
STC-LBS34POE-SWIR	GigE Vision	0.3 MP	242 FPS	1/4"
STC-LBS132POE-SWIR	GigE Vision	1.3 MP	84 FPS	1/2"
STC-LBS34U3V-SWIR	USB3 Vision	0.3 MP	260 FPS	1/4"
STC-LBS132U3V-SWIR	USB3 Vision	1.3 MP	134 FPS	1/2"
STC-LBS34CL-SWIR	Camera Link	0.3 MP	258 FPS	1/4"
STC-LBS132CL-SWIR	Camera Link	1.3 MP	125 FPS	1/2"